## Search Notes



Application/Control	No.

10520169

Applicant(s)/Patent Under Reexamination

BACON ET AL.

Examiner

Shin-Lin Chen

Art Unit

1632

## **SEARCHED**

Class	Subclass	Date	Examiner

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Search Notes	Date	Examiner
West, updated.	3-18-08	slc
West updated.	9-25-08	slc

## **INTERFERENCE SEARCH**

Class	Subclass	Date	Examiner

/Shin-Lin Chen/ Primary Examiner.Art Unit 1632

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